The 6th Waseda-NIMS International Symposium

Influence of growth conditions on optical, electrical and piezoelectric properties of Ca₃TaAl₃Si₂O₁₄ single crystals

°Xiuwei Fu^{1,2,*}, Encarnación G. Víllora¹, Yuuki, Kitanaka³, Yuji Noguchi³, Masaru Miyayama³, Kiyoshi Shimamura^{1,2}, Naoki Ohashi^{1,4}

¹ National Institute for Materials Science (NIMS), 1-1 Namiki, Tsukuba, Ibaraki 305-0044, Japan.
² Department of Nanoscience and Nanoengineering, Waseda University, 3-4-1 Okubo, Shinjuku, Tokyo 169-8555, Japan.

*E-mail address: fu.xiuwei@nims.go.jp

The piezoelectric langasite family (A₃BC₃D₂O₁₄) is attracting much attention for high temperature (HT) sensor applications. These crystals do not present any phase transition up to their melting points (1300-1500°C), exhibit good piezoelectric properties, are non-pyroelectric, and can be grown by the Czochralski (Cz) technique. Among them, the ordered Ca₃TaAl₃Si₂O₁₄ (CTAS) is of particular interest, since it is Ga-free, exhibits a high resistivity, and possesses a high thermal stability of dielectric and piezoelectric properties [1]. CTAS single crystals, grown so far with Ircrucibles, present a yellowish coloration, although according to their bandgap and constituents they should be colorless [2].

In this work, high quality CTAS single crystals were grown with Ir crucible and for the first time also with Pt crucibles by the Cz method (see e.g. Fig.1(a)). The effect of growth conditions on their optical, electrical and piezoelectric properties are determined. All single crystals were visually colorless and no absorption peaks were observed on their transmittance spectra. Figure 1(b) shows the resistivity of CTAS as a function of temperature. The resistivity of CTAS crystals grown under N₂ and N₂+1%O₂ at 400°C is around 6×10^{10} Ω cm, which is higher than that of CTAS grown under air $(1\times10^{10}$ Ω cm) and also than the reported one, especially at HT [1]. The activation energy Ea of the CTAS single crystals in this work is around 1.40 eV, which is smaller than the reported value of 1.64 eV [1].

This work has been partially supported by the Ministry of Education, Culture, Sports, Science and Technology (MEXT) Elements Strategy Initiative to Form Core Center of Japan.



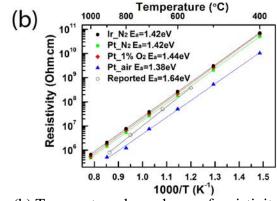


Fig. 1 (a) Photograph of CTAS grown under N₂+1%O₂; (b) Temperature dependence of resistivity.

Reference:

- [1] S. J. Zhang, Y. Q. Zheng, H. K. Kong, J. Xin, E. Frantz, and T. R. Shrout, *J. Appl. Phys.*, **105**, 114107 (2009).
- [2] J. Xin, Y. Q. Zheng, H. K. Kong, H. Chen, X. N. Tu, and E. W. Shi, *Cryst. Growth Des.*, **8** 2617-2619 (2008).

Department of Applied Chemistry, The University of Tokyo, 7-3-1 Hongo, Bunkyo, Tokyo 113-8656, Japan
 Materials Research Center for Element Strategy, Tokyo Institute of Technology, 4259 Nagatsuta, Midori, Yokohama 226-8503, Japan